



Chip-Scale Energy and Power... and Heat

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Getting the Heat Out

Dr. Thomas Kenny
DARPA/MTO
March 4, 2009



MICROSYSTEMS TECHNOLOGY OFFICE

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Exciting Technologies



Exciting Technologies

Packed into Tiny Systems





Exciting Technologies

Packed into Tiny Systems

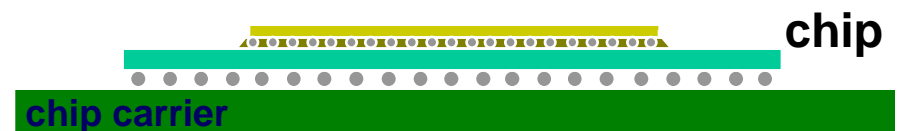
Generating a lot of Heat!



Microelectronics Packaging Today



- **Best modern technology in the electronics layer**





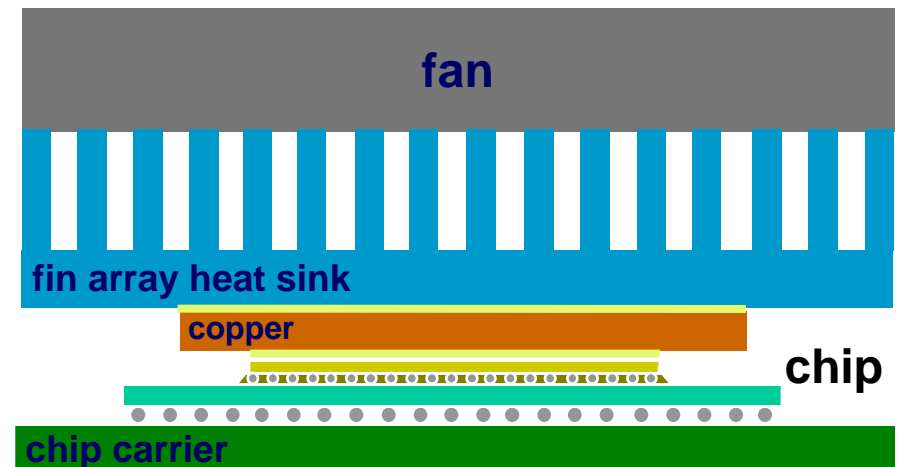
Microelectronics Packaging Today



- Best modern technology in the electronics layer

Ancient “technology” in the thermal layer

(side view)





Microelectronics Packaging Today



The growing size of the thermal solution is a source of :

- **Mechanical failure problems**
- **Weight problems**
- **System size for multi-processor systems (servers)**
- **Significant added cost**
- **Reliability problems (fan)**
- **Crowding away the power conditioning elements**

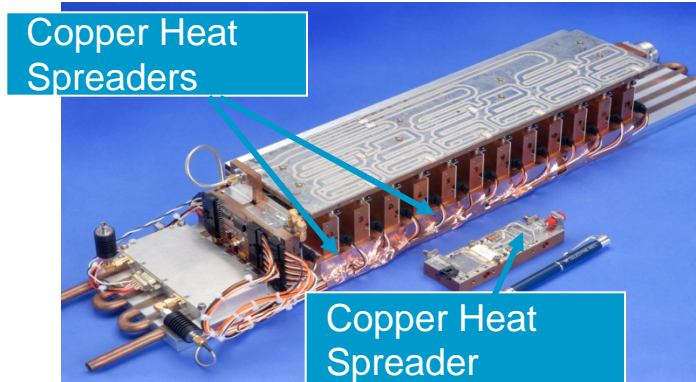
**Things are bad in the commercial sector,
and MUCH WORSE in the DoD...**



Examples of DoD Systems Constrained by Thermal Management

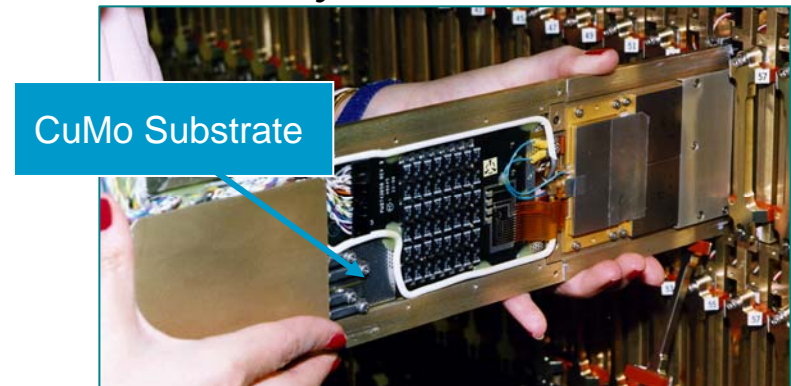


Teledyne's ALQ-99 TWT Replacement Module



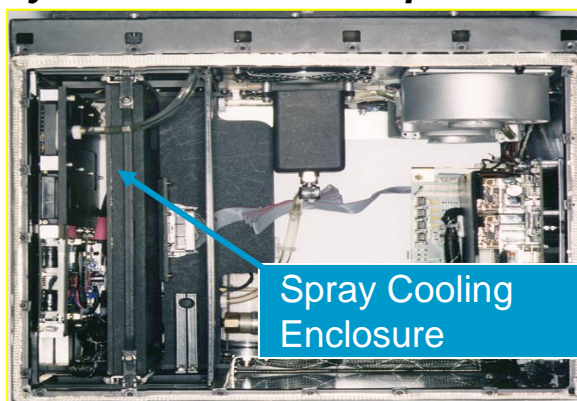
Solid Copper Spreaders used on High-G Platforms add Significant Weight to Avionics

Raytheon's High Power Density Phased Arrays



CuMo MCM Substrates Prevent Further Power Scaling in Array Radar Systems

Cray J90 Airborne Computer

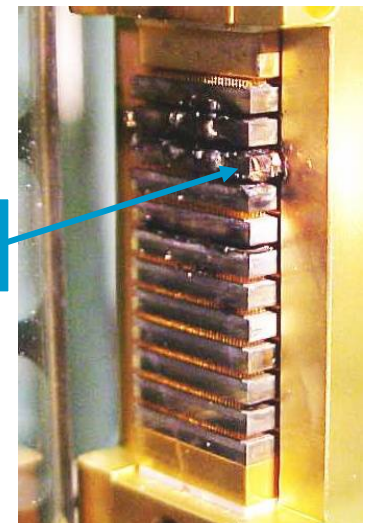


Large, Heavy, Complex Facilities for Spray Cooling

Diode Laser Bar Thermal Overload

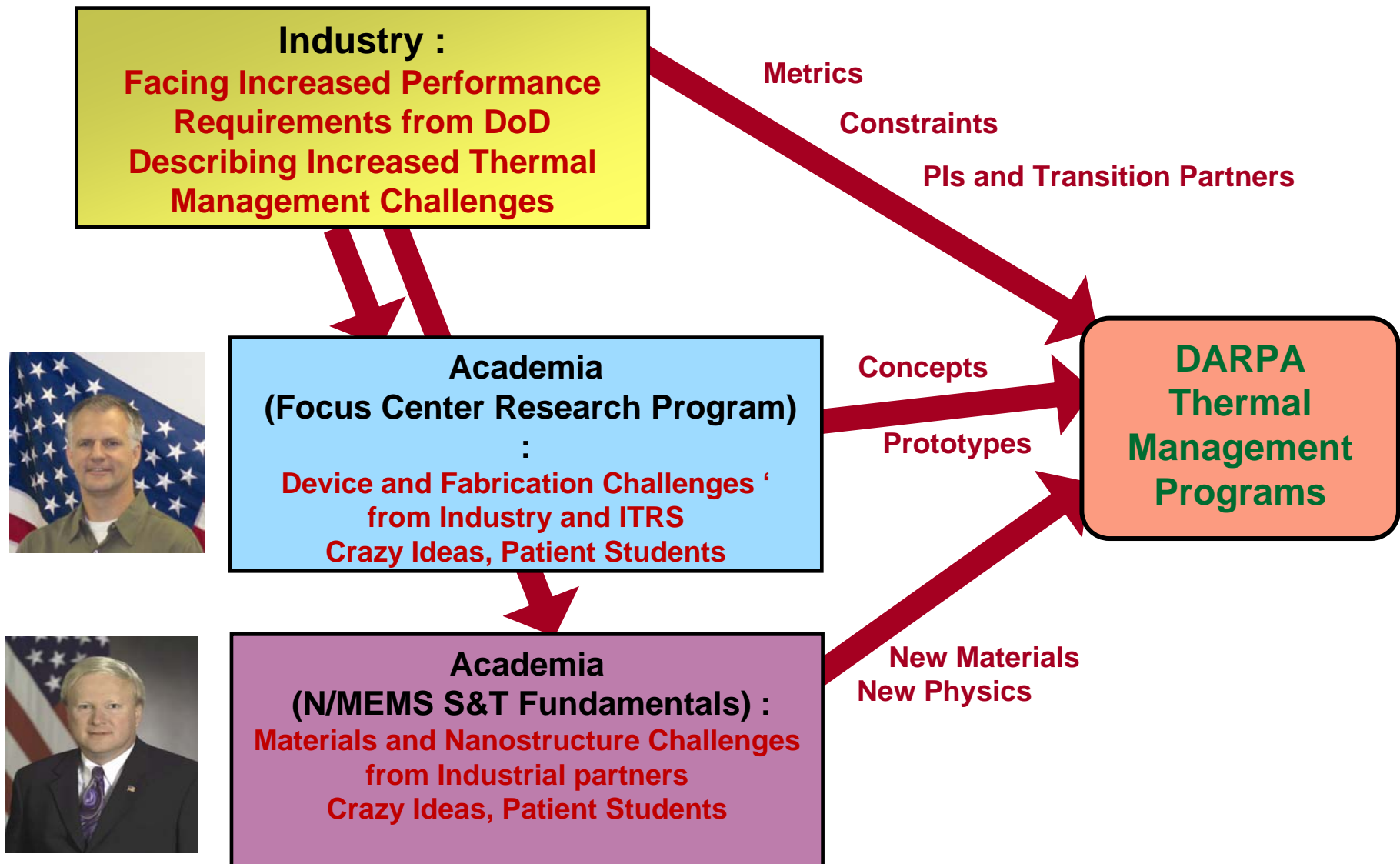
Diode Bar

Solder Interface Imposes High Assembly Temperature or High Thermal Resistance





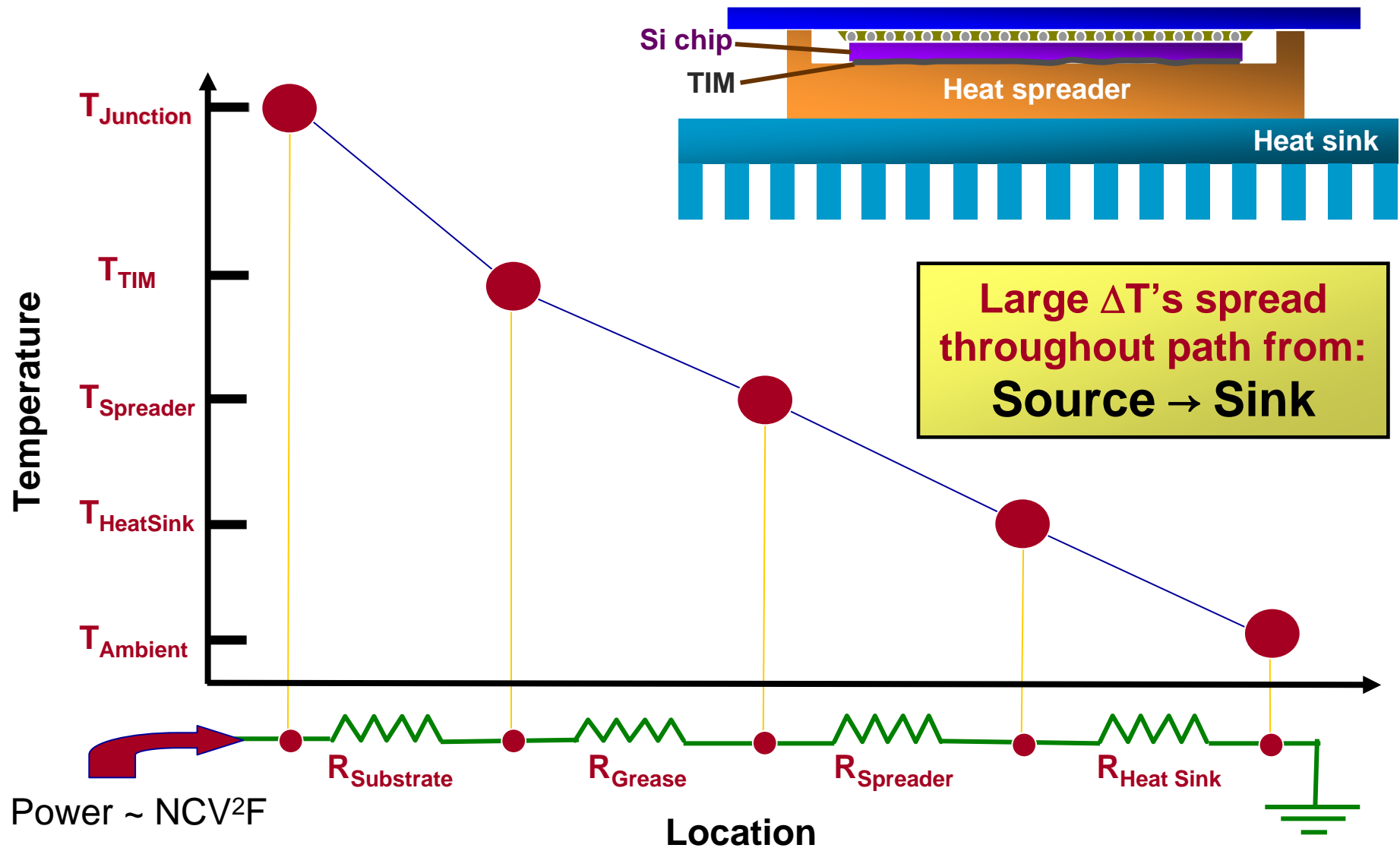
DARPA Approach to Thermal Management Challenges





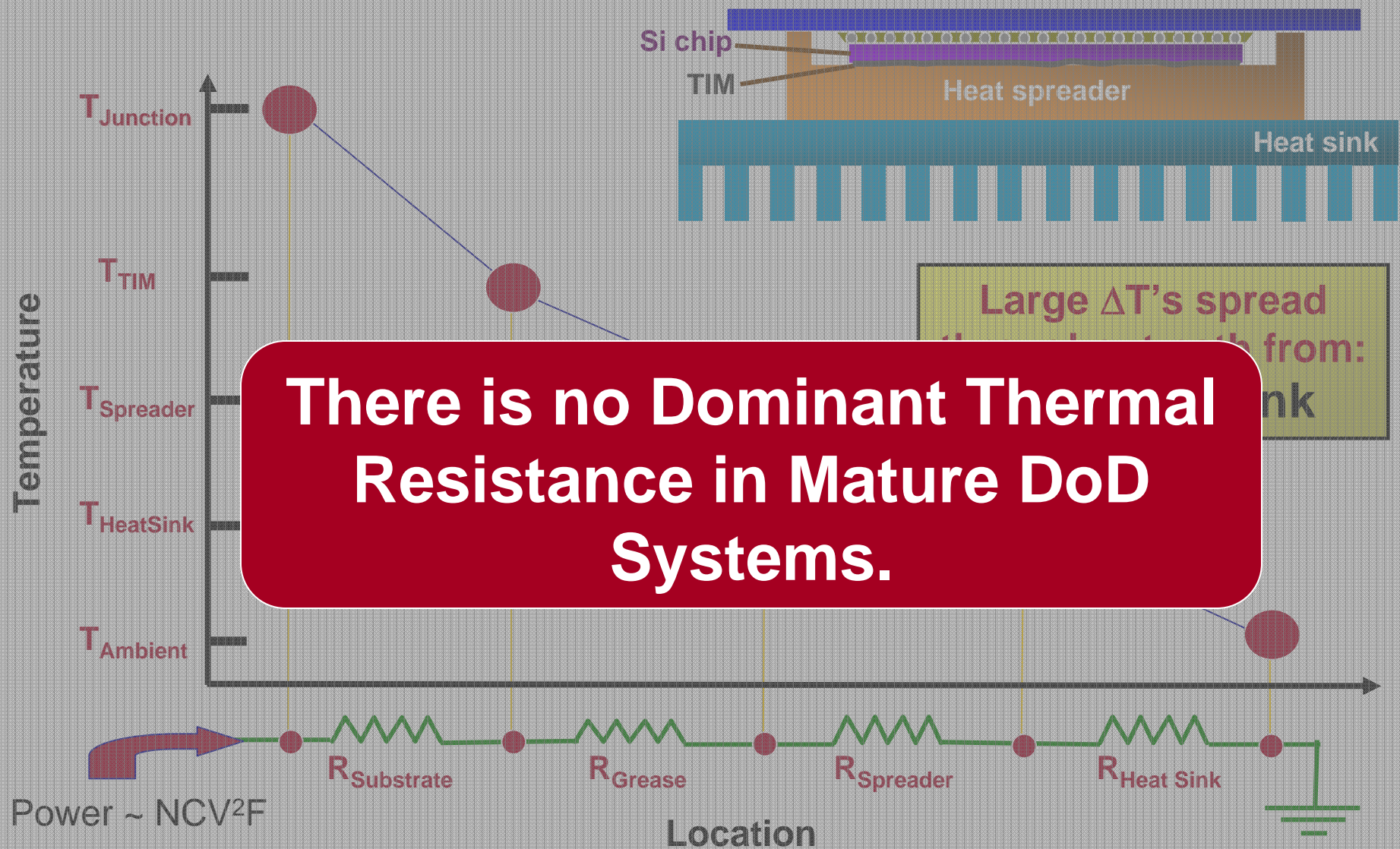
Thermal Resistance Breakdown

Where is the Problem?



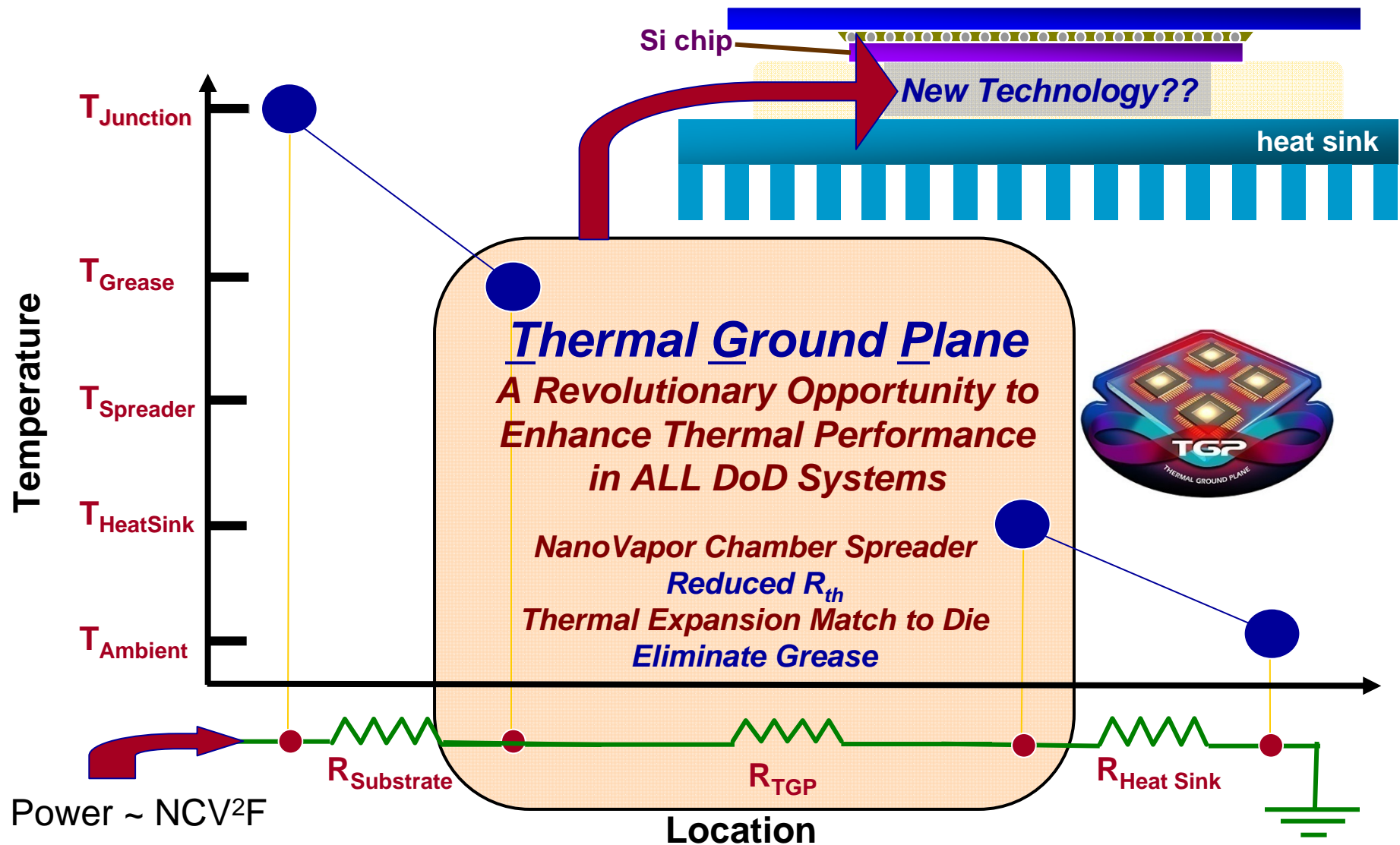


Thermal Resistance Breakdown Where is the Problem?





Thermal Ground Plane (TGP)

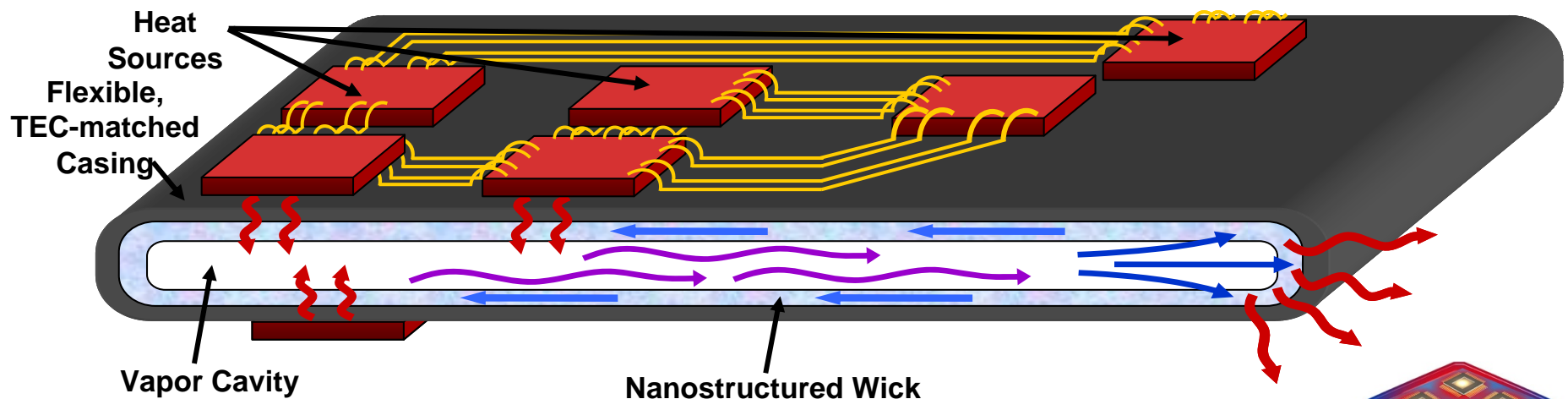




Thermal Ground Plane (TGP)



TGP Program Vision : A new 2-D, thin, lightweight MCM substrate incorporating modern and nanostructured materials to achieve vastly superior thermal conduction & possessing all mechanical properties necessary for hard-mounting ICs.

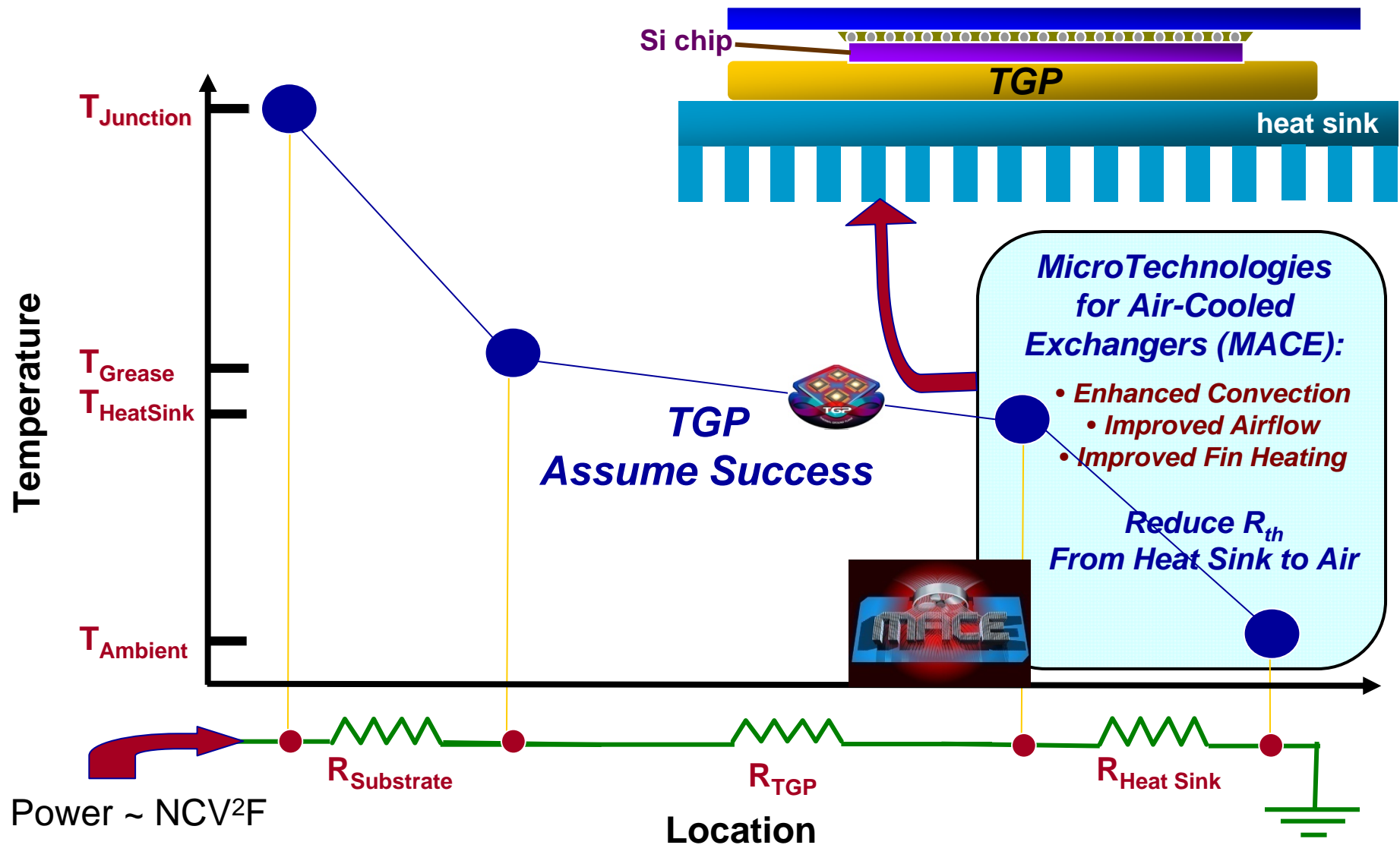


- Extreme lateral thermal conduction, 100X above current MCM substrates
- Large 2-D area, <1 mm thick, Operation up to 20g
- Nanostructured wick for enhanced heat transfer and fluid transport
- Structural, flexible, thin, & light-weight materials that match the TEC of Si, GaAs, or GaN
- 2-phase heat transfer to eliminate load-driven thermal non-uniformity across substrate

Program Kickoff 1/08



A New Thermal Opportunity

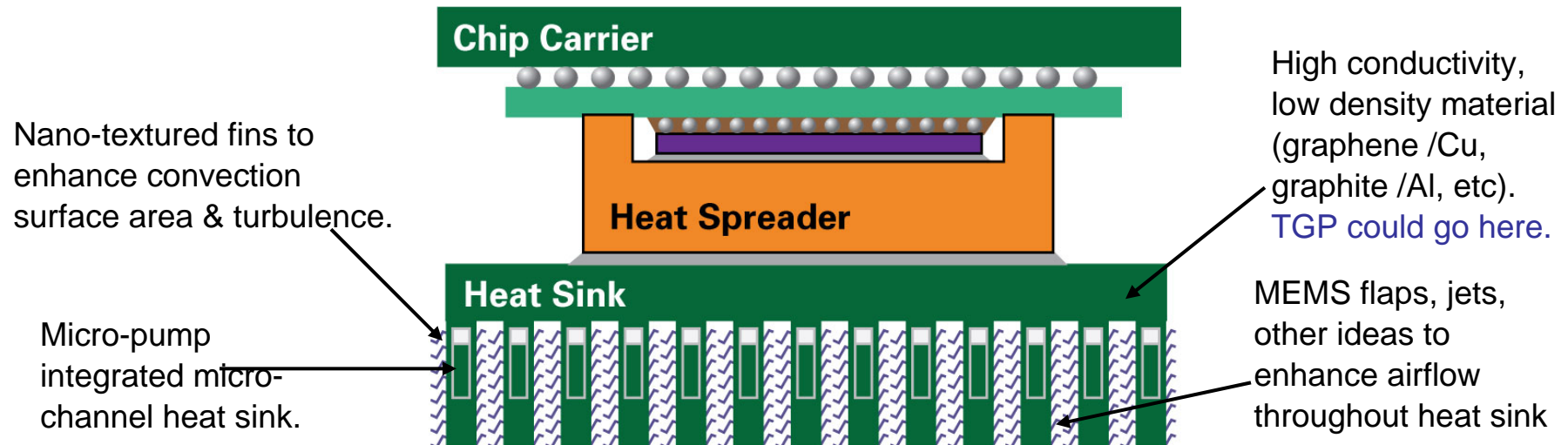




Microtechnologies for Air Cooled Exchangers (MACE)



MACE Program Vision : Develop new technologies to enhance the performance of heat sinks by reducing thermal resistance and airflow resistance. MACE will enable lighter, more compact systems with better thermal performance. MACE complements the Thermal Ground Plane (TGP) program.



MACE Goals:

- Reduction in Thermal Resistance from Heat Sink to Air
- Reduction in Airflow Resistance through Heat Sink
- Use of Direct Air Cooling in Dense High-Power Systems
- Reduced Power Consumption in Cooling Systems



Program Kickoff 1/09.

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MACE Program Goals



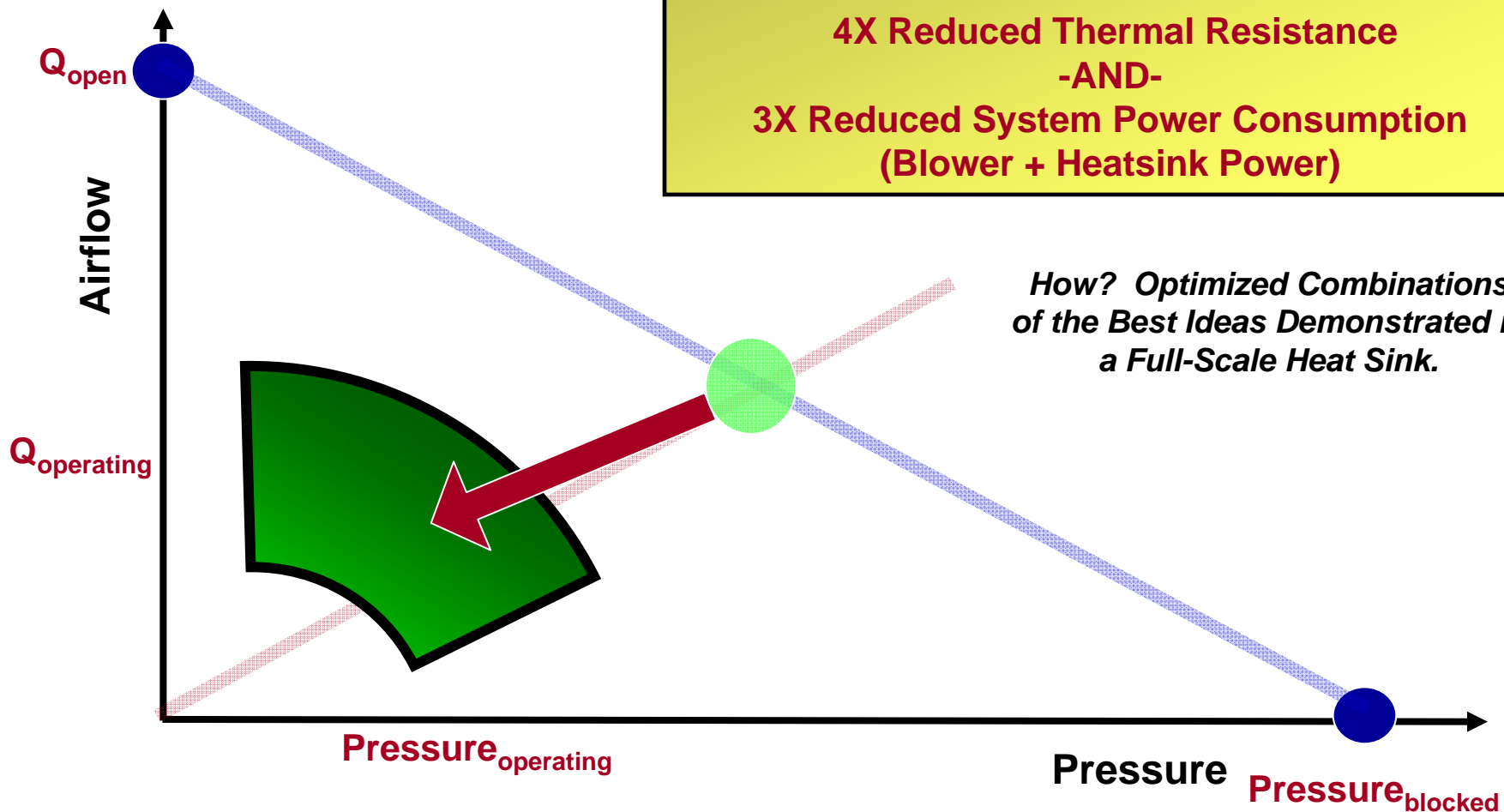
MACE Goals :

**Enable New System Operating Points
At Better Performance and Lower Power**

4X Reduced Thermal Resistance

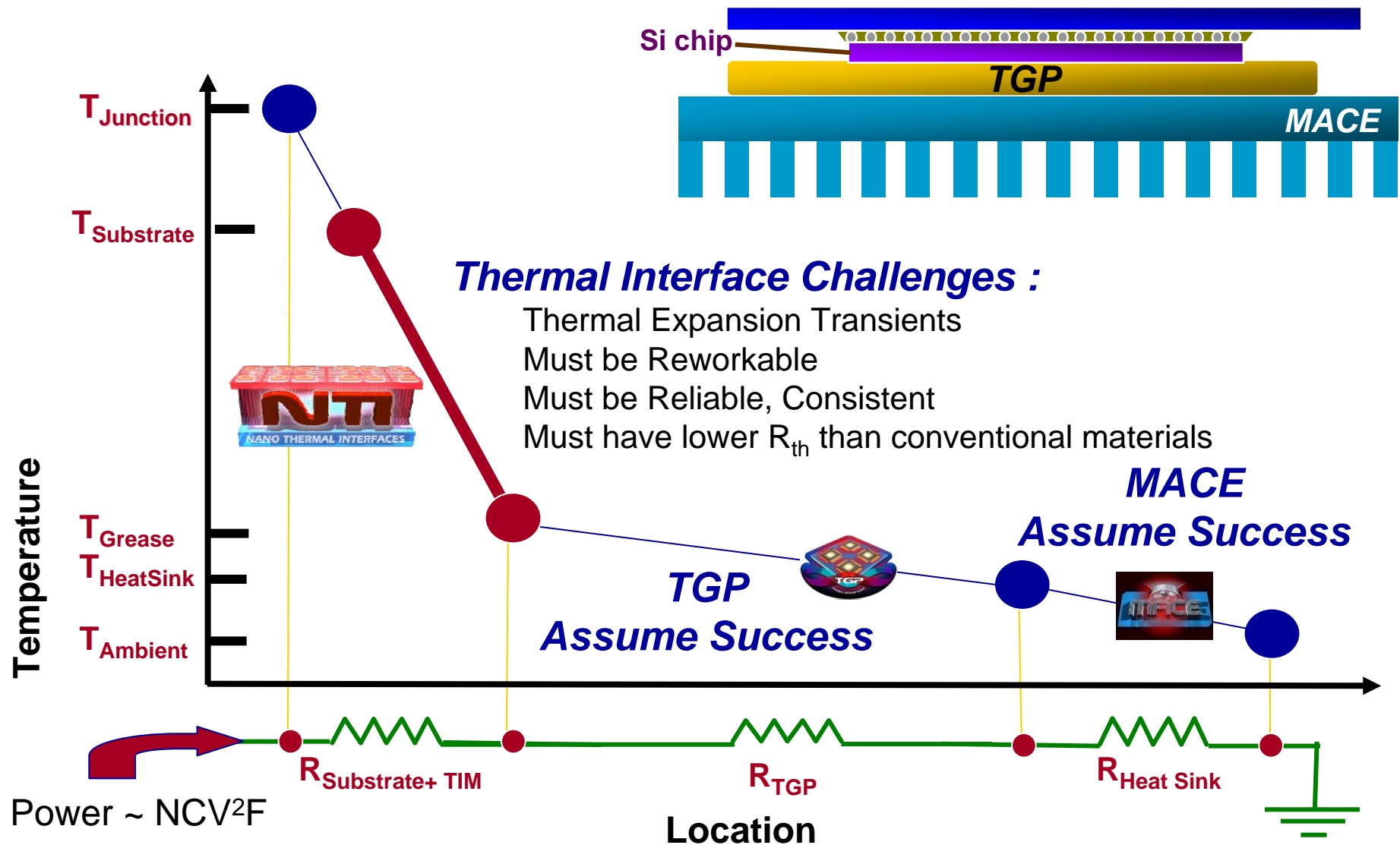
-AND-

**3X Reduced System Power Consumption
(Blower + Heatsink Power)**





The Next Thermal Opportunity





NanoThermal Interfaces (NTI)

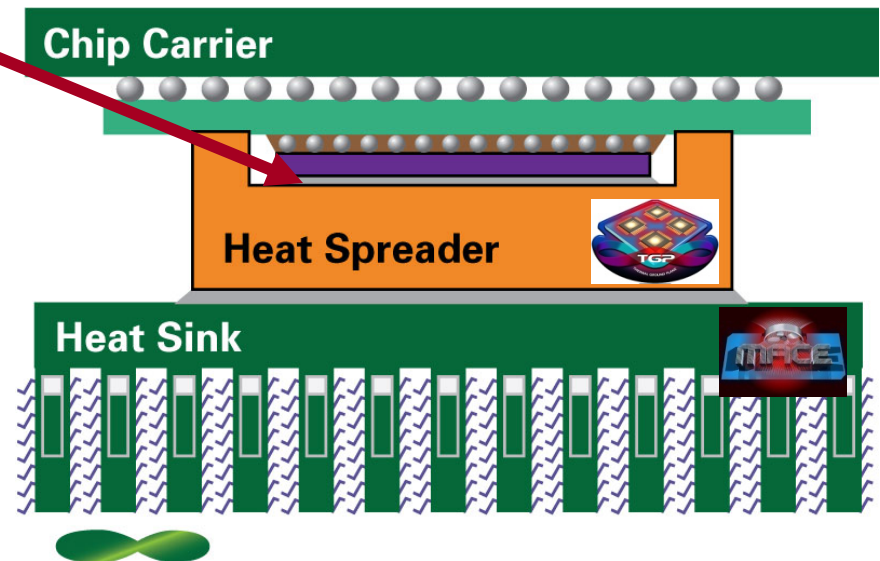


Thermal Interface materials (TIM):

Resistance of thermal interface materials – emerging bottleneck in thermal management of all DoD systems.

Success in TGP and MACE will shift focus to this layer.

Existing solutions (epoxy, grease, In, Solder) Not Doing the Job!



TIM Must Haves :

- Lower Thermal Resistance (10 W/m•K typical. 5x reductions would be valuable)
- Easily Reworkable (Chips Fail)
- Allow Lateral Shear (chips get hot before the rest of the system)
- Long-Term Reliability and Consistency from Chip to Chip

Opportunities :

- *Nanotube/Nanowire materials may be able to meet this challenge*
- *Preliminary work in NSF, ONR, DARPA (MARCO), etc is promising*

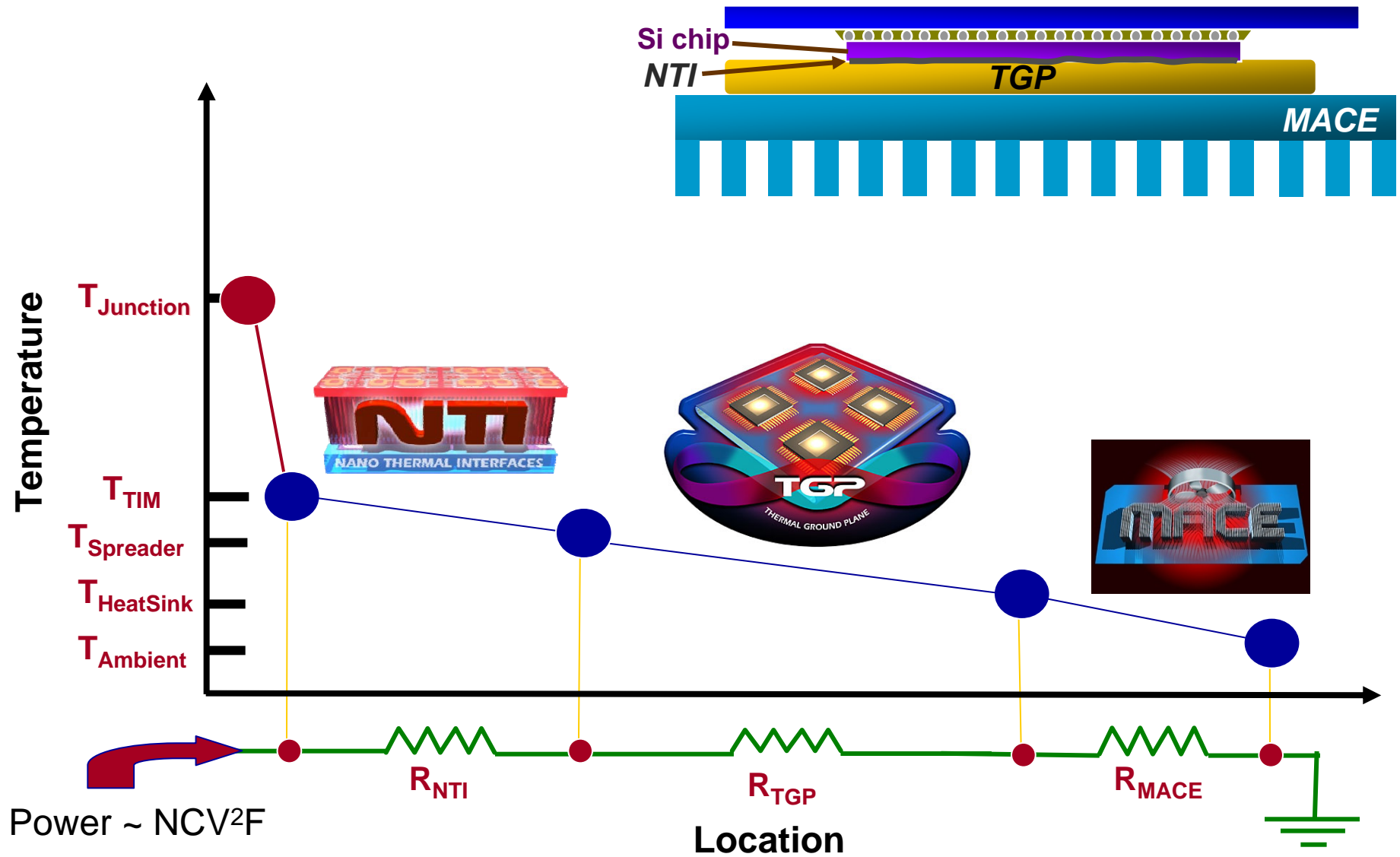


Program Kickoff 4/09.

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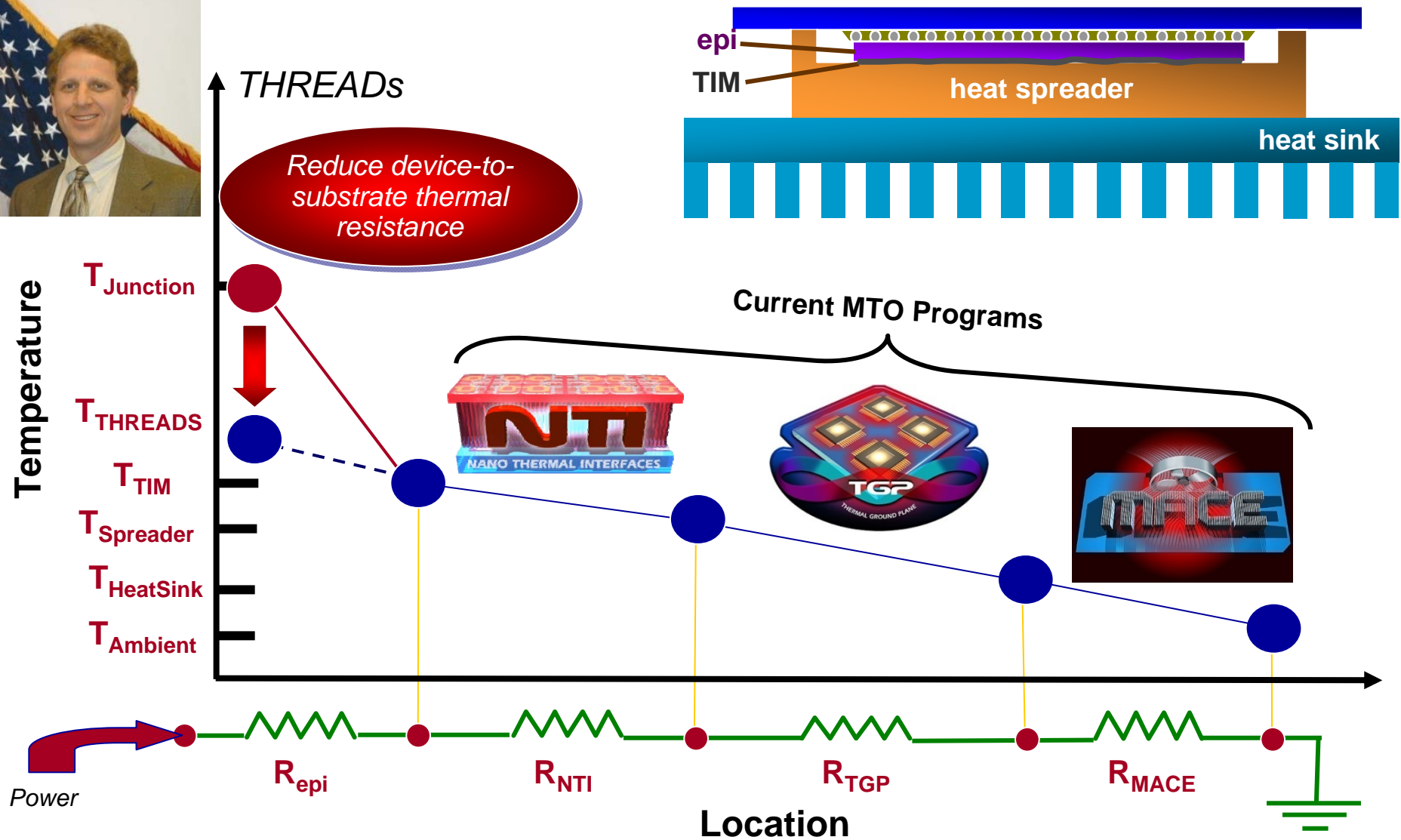


Thermal Management Portfolio





Technologies for Heat Removal from Electronics at the Device Scale (THREADS)





Technologies for Heat Removal from Electronics at the Device Scale (THREADS)



High Thermal Conductivity Over-layer for Heat Removal from Topsides of Devices

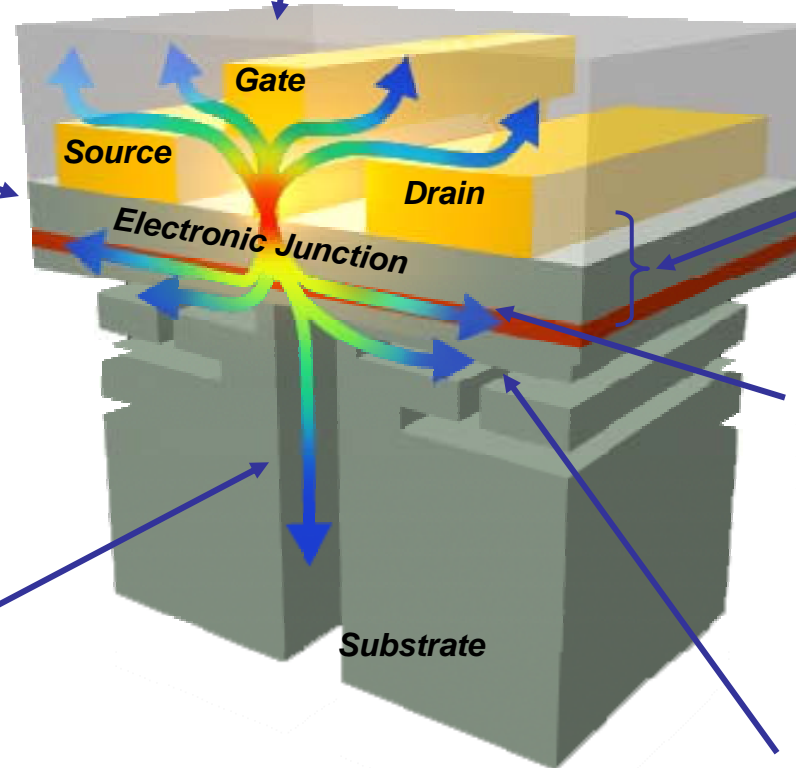
- High thermal conductivity in deposited material
- Conformal coverage with no gaps

High Thermal Conductivity Substrates

- Integrate lattice-mismatched heat spreaders
- Eliminate thermal interface resistance
- Match coefficient of thermal expansion of electronic material

Embedded Thermal Vias

- Micro-machined vias within ~ 1 micron of junction
- High thermal conductivity conformal fill materials
- Low coupling resistance for junction-to-thermal via, thermal via-to-heat sink



$\sim 1\mu\text{m}$ thickness

Anisotropic Heat Transport

- Efficient nanoscale phonon channel
- Long LO phonon lifetime (3ps)
- Extremely low electrical contact resistance

Active Liquid Cooling

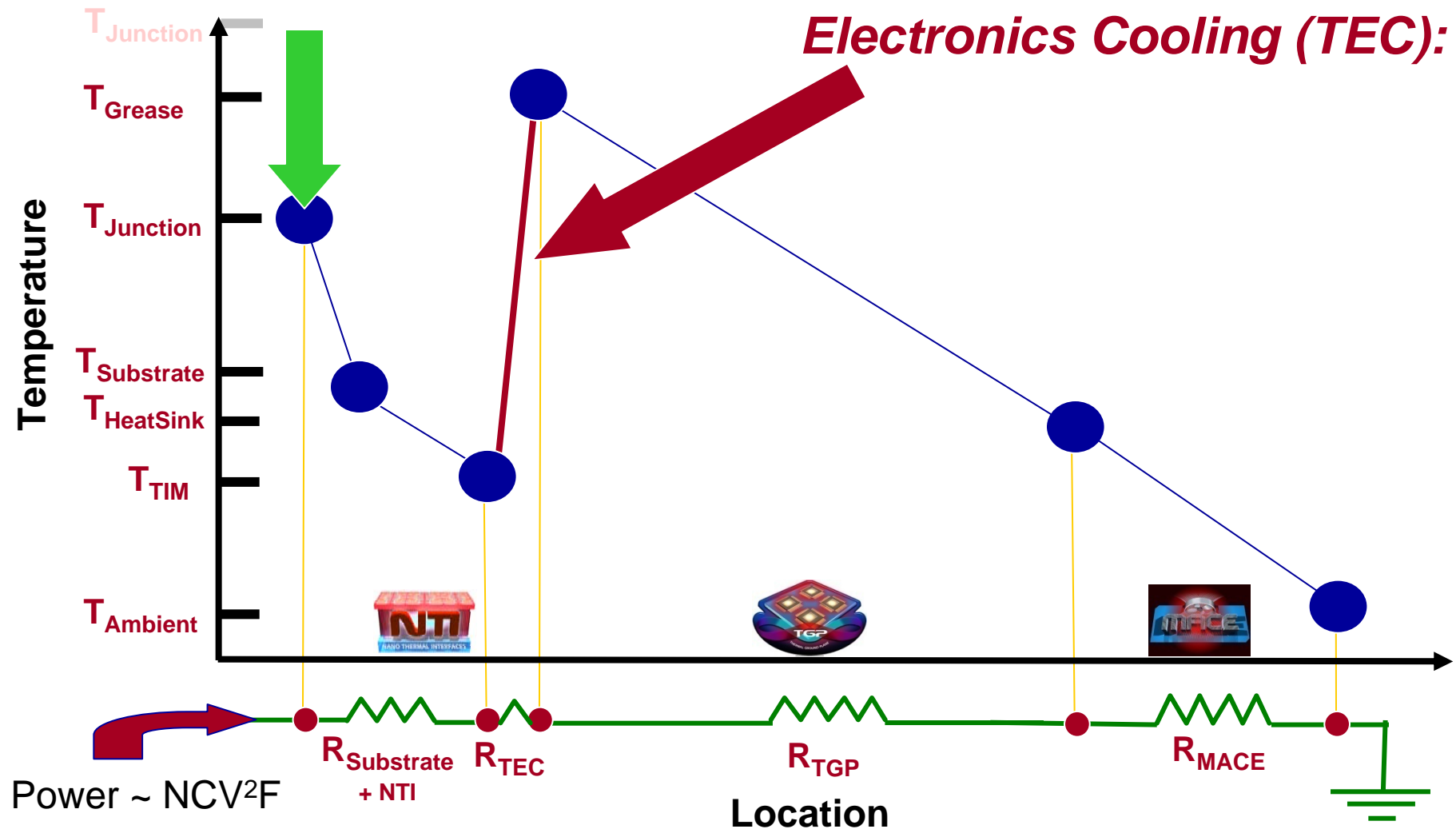
- Eliminate impact on device electrical properties due to time varying dielectric constant of liquid



Thermoelectrics for Electronics Cooling (TEC)



Thermoelectrics for Electronics Cooling (TEC):

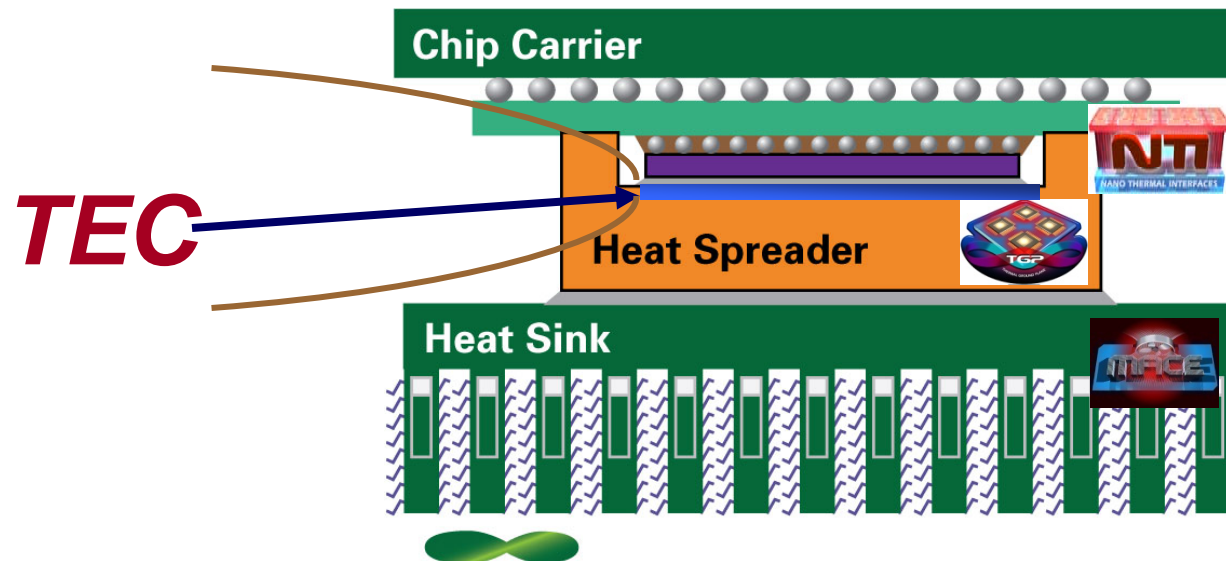




Thermoelectrics for Electronics Cooling (TEC)



TEC Vision : Enable greater power utilization margins in electronic materials while also increasing device reliability. Integrate TEC design with NTI, TGP, and MACE.



TEC Goals:

- Build complete modules with all interfaces that demonstrate TEC benefits
- Reduce ΔT of junction temperature for electronic devices
- Further increase electronic device power
- Increase device reliability
- Incorporate system with NTI, TGP, MACE designs for optimal thermal management system



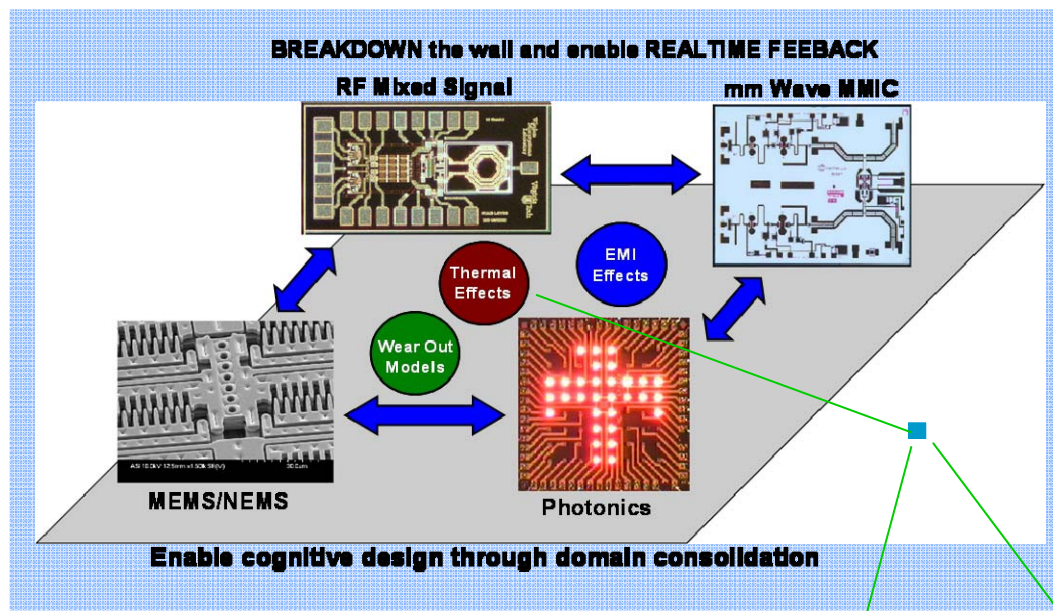
METACAD and DANTE Visions



- ➔ **METACAD** – Cognitive Design Support for Complex Systems
- ➔ **DANTE** – Integrated Thermal + Electrical IC Design Support



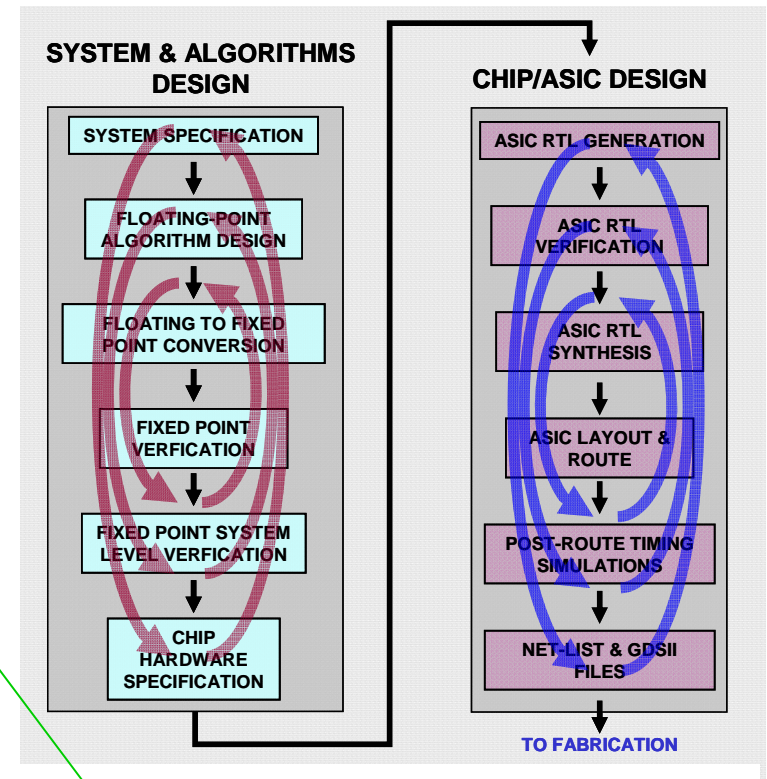
METACAD



Key Technologies

- NeoCAD/PAC/3DIC & Beyond
- Human/Machine Interaction Algorithms (Cognition)
- Models: Architecture, & Physical (Electrical, Thermal, Mechanical)

DANTE

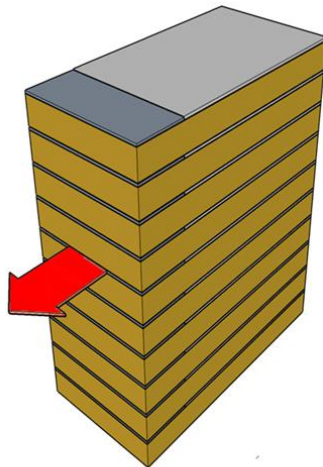


Key Technologies

- Models: Architecture & Thermal
- Multi-Physics Interactions included



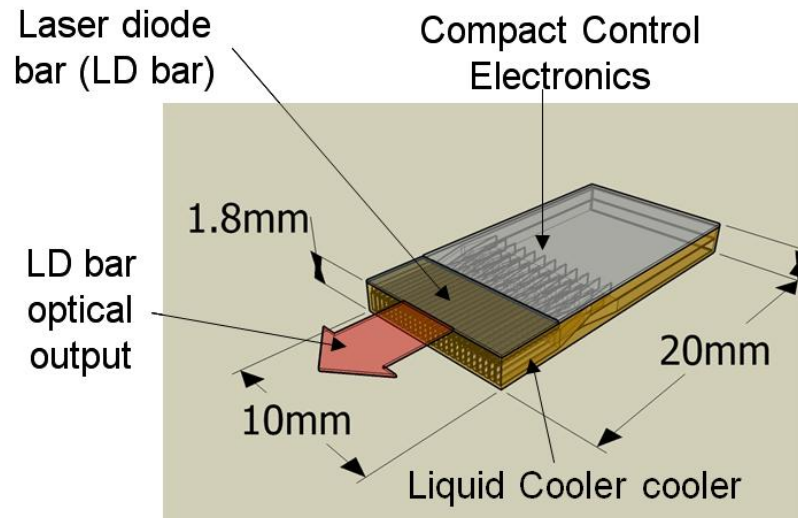
Direct Cooling of High Flux Laser Diode Elements



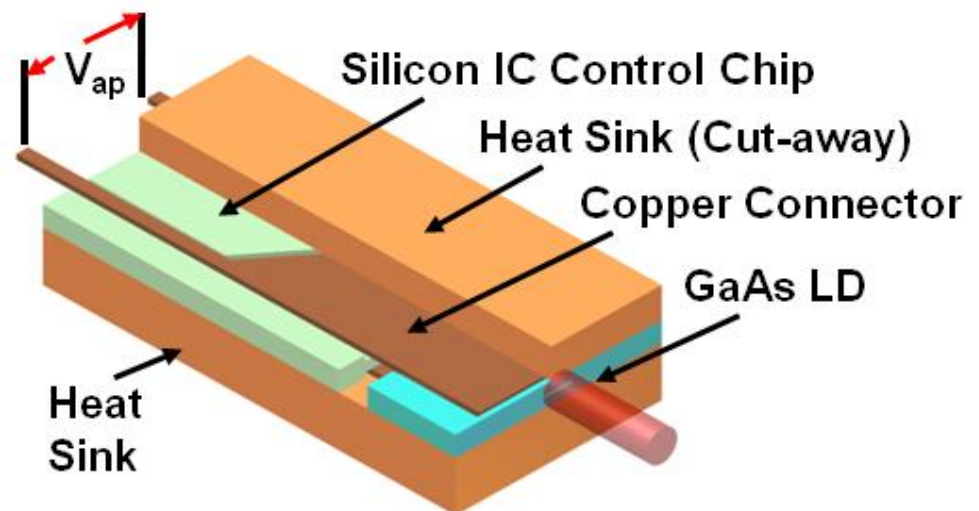
LDA Stack

Advantages include:

- **Laser diode protection at the single emitter level**
 - Intelligent protection is easier on a single emitter level
 - Enable control of current to each LD
 - Path to phased array LDAs and 3-4X higher power on target
- **35K lower facet temperature resulting in 10X longer life or**
- **5X improvement in performance resulting in ~1,000 Watts/cm-bar**



Single bar on 1.8 mm thick cooler





DARPA Organization



Agency Director
Deputy Director

\$3B/Year

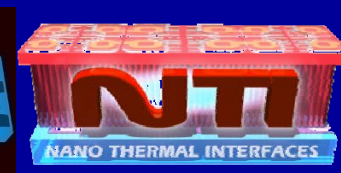
\$???/Year

~80 other program
managers

Mostly busy creating
thermal management
problems in the DoD

Tom Kenny
MTO Program Manager

Trying to solve some
thermal management
problems in the DoD



???

MICROSYSTEMS TECHNOLOGY OFFICE

MTD SYMPOSIUM

The logo for the Microsystems Technology Office (MTO) Symposium. It features the letters 'MTD' in a large, bold, metallic font. The 'D' is stylized with a globe inside it, and the word 'DARPA' is written across the globe. Circuit traces extend from the 'M' and 'D'. Below 'MTD' is the word 'SYMPOSIUM' in a smaller, white, sans-serif font. The entire logo is set against a dark background with a reflection effect below it.

BUILDING THE FUTURE
FROM THE INSIDE OUT

The background of the poster is a collage of various technological and infrastructure elements. On the left, there's a large satellite dish and a solar panel array. In the center, a complex antenna structure is visible. On the right, there's a large, modern building with a glass facade. The entire background is set against a blue gradient with a grid pattern. A thin blue line with three blue spheres runs horizontally across the middle of the image, passing behind the text.

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